Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/066,766	TAKANO ET AL.	
Examiner	Art Unit	
TAN TRINH	2684	

SEARCHED					
Class	Subclass	Date	Examiner		
455	522	4/7/2006	тт		
	69				
	442				
	453				
	452.2				
	441				
	456.4				
	13.4				
	515				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
PG-PUB Text search (see print out)		4/7/2006	тт		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	4/7/2006	тт	
Nick Corsaro	9/30/2004	ALAN	
Nay Maung	7/1/2005	ALAN	
Vo, Nguyen	3/31/2006	тт	
Nick Coraso	4/7/2006	ТТ	
Interference Search	4/7/2006	тт	